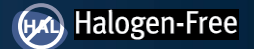


# EPC2067 – Enhancement Mode Power Transistor

 $V_{DS}, 40\text{ V}$ 
 $\text{Max } R_{DS(on)}, 1.55\text{ m}\Omega$ 
 $I_D, 69\text{ A}$ 


Revised October 21, 2021

Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low  $R_{DS(on)}$ , while its lateral device structure and majority carrier diode provide exceptionally low  $Q_G$  and zero  $Q_{RR}$ . The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.



## Maximum Ratings

PARAMETER		VALUE	UNIT
$V_{DS}$	Drain-to-Source Voltage (Continuous)	40	V
	Drain-to-Source Voltage (up to 10,000 5 ms pulses at 150°C)	48	
$I_D$	Continuous ( $T_A = 25^\circ\text{C}$ )	69	A
	Pulsed ( $25^\circ\text{C}$ , $T_{PULSE} = 300\ \mu\text{s}$ )	409	
$V_{GS}$	Gate-to-Source Voltage	6	V
	Gate-to-Source Voltage	-4	
$T_J$	Operating Temperature	-40 to 150	°C
$T_{STG}$	Storage Temperature	-40 to 150	

## Thermal Characteristics

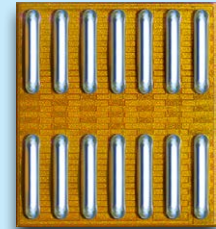
PARAMETER		TYP	UNIT
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	°C/W
$R_{\theta JB}$	Thermal Resistance, Junction-to-Board	1.4	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (Note 1)	48	

Note 1:  $R_{\theta JA}$  is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See [https://epc-co.com/epc/documents/product-training/Appnote\\_Thermal\\_Performance\\_of\\_eGaN\\_FETs.pdf](https://epc-co.com/epc/documents/product-training/Appnote_Thermal_Performance_of_eGaN_FETs.pdf) for details.

## Static Characteristics ( $T_J = 25^\circ\text{C}$ unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-to-Source Voltage	$V_{GS} = 0\text{ V}$ , $I_D = 1.1\text{ mA}$	40			V
$I_{DSS}$	Drain-Source Leakage	$V_{GS} = 0\text{ V}$ , $V_{DS} = 32\text{ V}$	0.01	0.9		mA
$I_{GSS}$	Gate-to-Source Forward Leakage	$V_{GS} = 5\text{ V}$	0.002	4		
	Gate-to-Source Forward Leakage <sup>#</sup>	$V_{GS} = 5\text{ V}$ , $T_J = 125^\circ\text{C}$	0.2	9		
	Gate-to-Source Reverse Leakage	$V_{GS} = -4\text{ V}$	0.01	1		
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 18\text{ mA}$	0.7	1	2.5	V
$R_{DS(on)}$	Drain-Source On Resistance	$V_{GS} = 5\text{ V}$ , $I_D = 37\text{ A}$	1.3	1.55		mΩ
$V_{SD}$	Source-Drain Forward Voltage <sup>#</sup>	$I_S = 0.5\text{ A}$ , $V_{GS} = 0\text{ V}$	1.2			V

<sup>#</sup> Defined by design. Not subject to production test.



Die Size: 2.85 x 3.25 mm

EPC2067 eGaN® FETs are supplied only in passivated die form with solder bars.

## Applications

- High frequency DC-DC converters
- BLDC motor drives
- Sync rectification for AC-DC and DC-DC

## Benefits

- High power density
- High efficiency
- No reverse recovery
- Ultra Low  $Q_G$
- Small footprint
- High frequency capability

Scan QR code or click link below for more information including reliability reports, device models, demo boards!



<https://l.ead.me/EPC2067>

Dynamic Characteristics <sup>#</sup> (T <sub>J</sub> = 25°C unless otherwise stated)						
PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
C <sub>ISS</sub>	Input Capacitance	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V		2178	3267	pF
C <sub>RSS</sub>	Reverse Transfer Capacitance			24		
C <sub>OSS</sub>	Output Capacitance			1071	1607	
C <sub>OSS(ER)</sub>	Effective Output Capacitance, Energy Related (Note 2)	V <sub>DS</sub> = 0 to 20 V, V <sub>GS</sub> = 0 V		1597		
C <sub>OSS(TR)</sub>	Effective Output Capacitance, Time Related (Note 3)			1860		
R <sub>G</sub>	Gate Resistance			0.4		Ω
Q <sub>G</sub>	Total Gate Charge	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 5 V, I <sub>D</sub> = 37 A		17.1	22.3	nC
Q <sub>GS</sub>	Gate-to-Source Charge	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 37 A		5.3		
Q <sub>GD</sub>	Gate-to-Drain Charge			2		
Q <sub>G(TH)</sub>	Gate Charge at Threshold			4.2		
Q <sub>OSS</sub>	Output Charge	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V		37	56	
Q <sub>RR</sub>	Source-Drain Recovery Charge			0		

# Defined by design. Not subject to production test.  
 All measurements were done with substrate connected to source.  
 Note 2: C<sub>OSS(ER)</sub> is a fixed capacitance that gives the same stored energy as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.  
 Note 3: C<sub>OSS(TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C

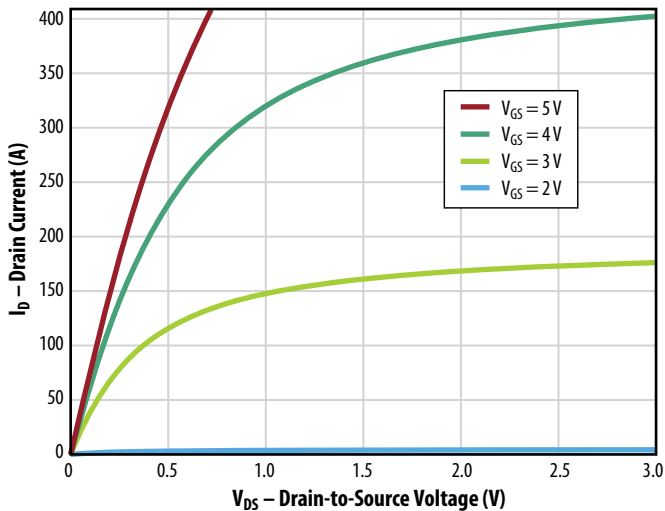


Figure 2: Typical Transfer Characteristics

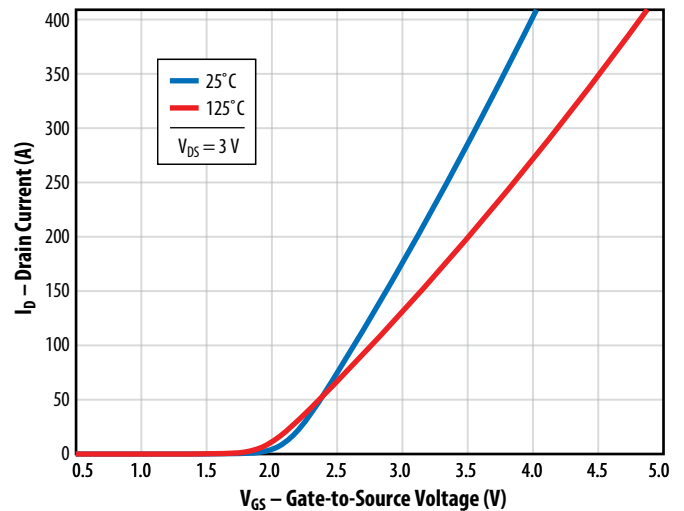


Figure 3: Typical R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Drain Currents

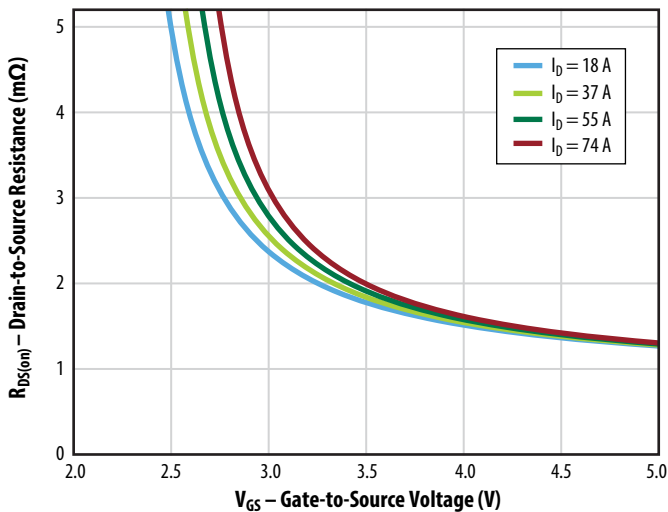


Figure 4: Typical R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

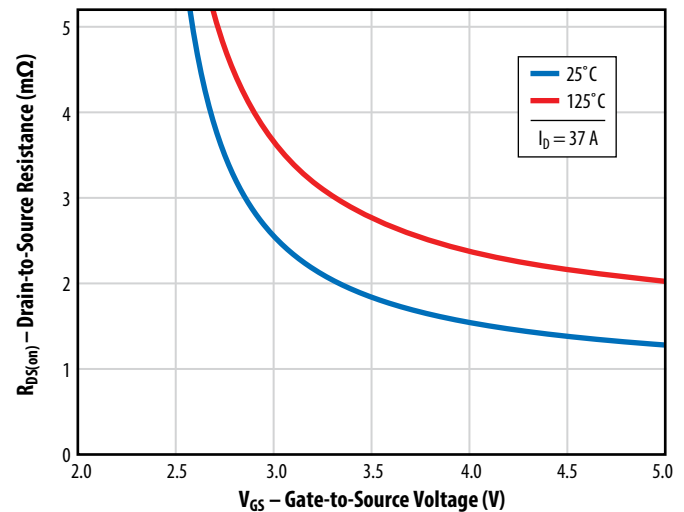


Figure 5a: Typical Capacitance (Linear Scale)

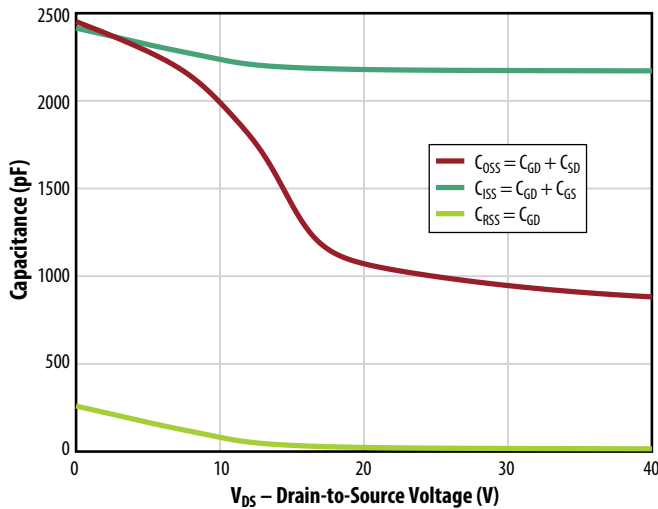


Figure 5b: Typical Capacitance (Log Scale)

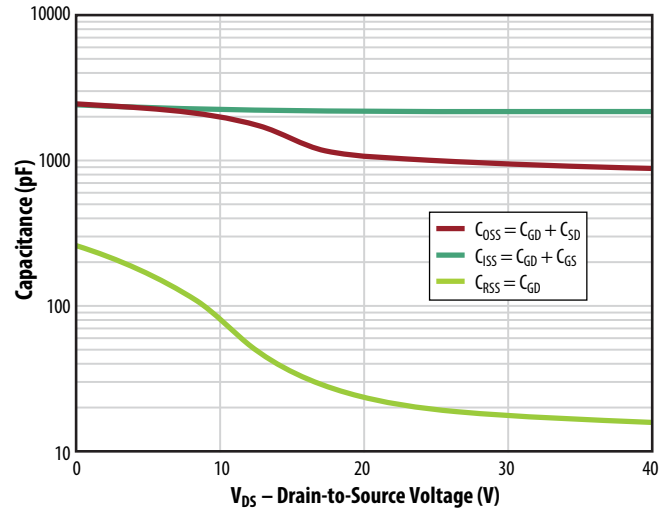


Figure 6: Typical Output Charge and Coss Stored Energy

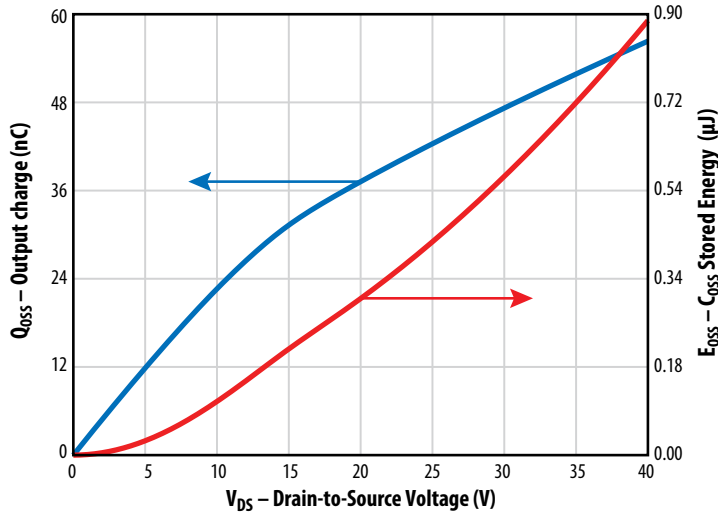


Figure 7: Typical Gate Charge

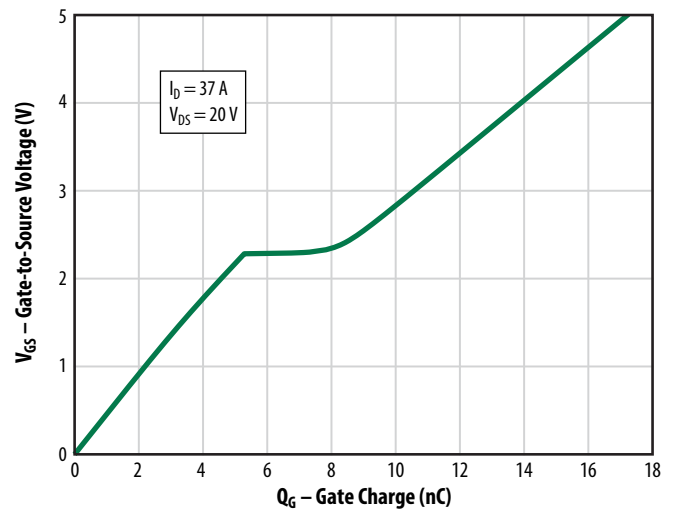


Figure 8: Typical Reverse Drain-Source Characteristics

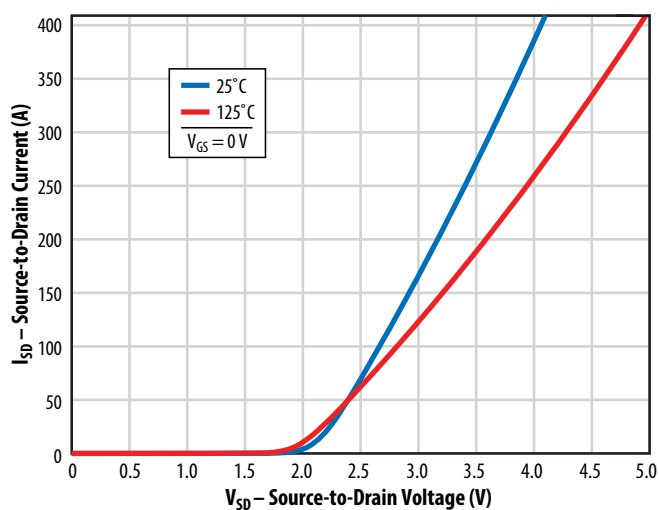
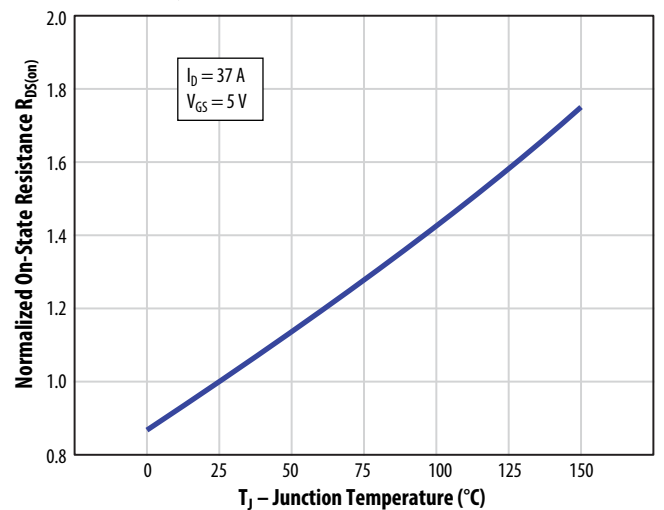


Figure 9: Typical Normalized On-State Resistance vs. Temp.



Note: Negative gate drive voltage increases the reverse drain-source voltage. EPC recommends 0 V for OFF.

Figure 10: Typical Normalized Threshold Voltage vs. Temperature

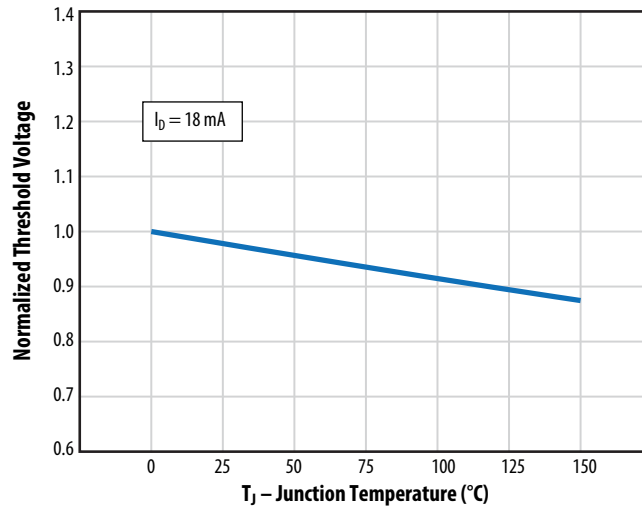


Figure 11: Typical Transient Thermal Response Curves

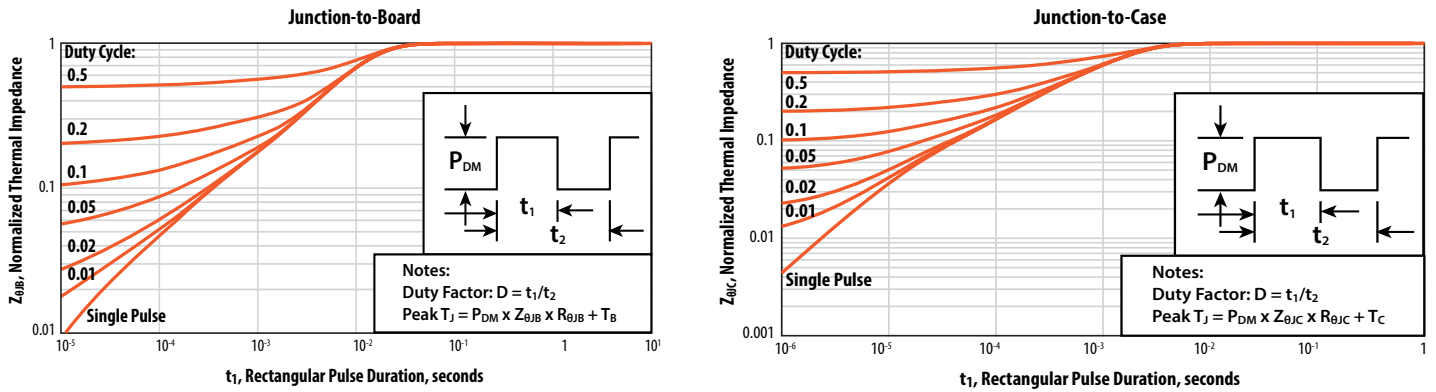
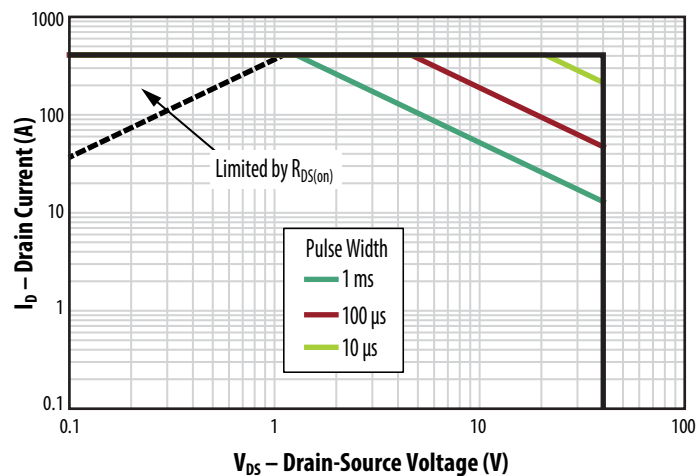
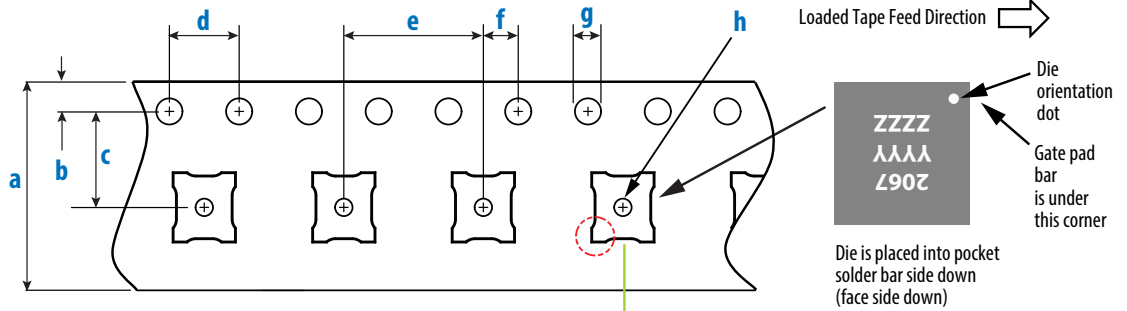
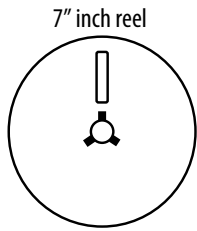


Figure 12: Safe Operating Area

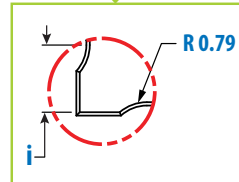


**TAPE AND REEL CONFIGURATION**

8 mm pitch, 12 mm wide tape on 7" reel



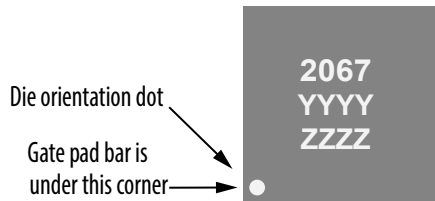
EPC2067 (Note 1)	Dimension (mm)		
	Target	MIN	MAX
a	12.00	11.90	12.30
b	1.75	1.65	1.85
c (Note 2)	5.50	5.45	5.55
d	4.00	3.90	4.10
e	8.00	7.90	8.10
f (Note 2)	2.00	1.95	2.05
g	1.50	1.50	1.60
h	1.00	0.95	1.05
i	1.27		



Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/ JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

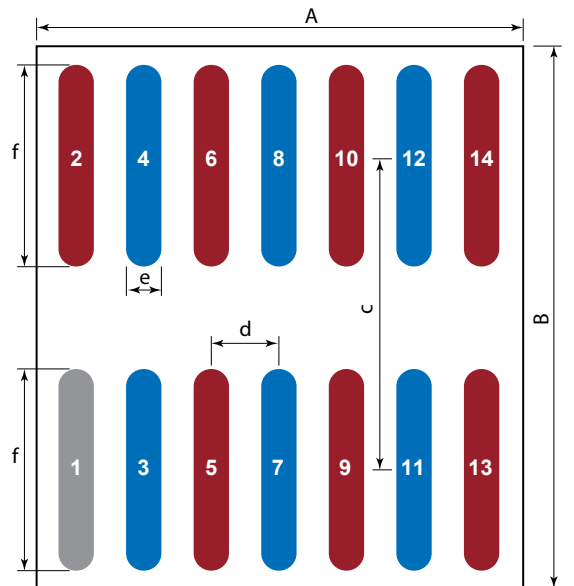
**DIE MARKINGS**



Part Number	Laser Markings		
	Part # Marking Line 1	Lot Date Code Marking Line 2	Lot Date Code Marking Line 3
EPC2067	2067	YYYY	ZZZZ

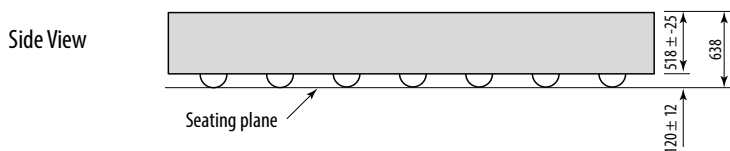
**DIE OUTLINE**

Solder Bump View

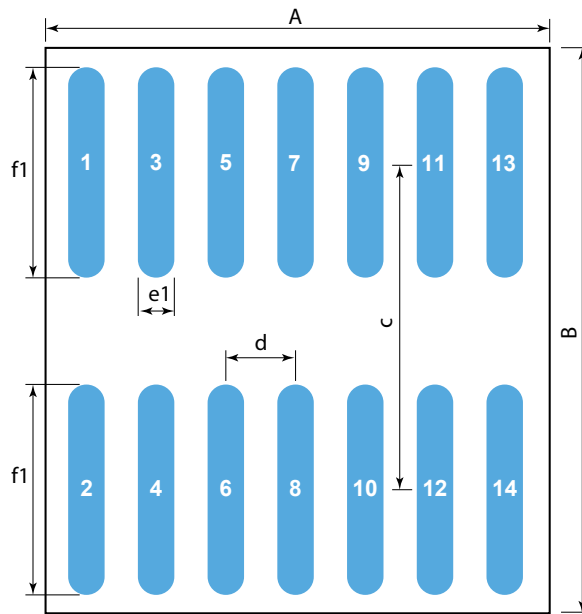


DIM	Micrometers		
	MIN	Nominal	MAX
A	2820	2850	2880
B	3220	3250	3280
c		1805	
d		400	
e		200	
f		1195	

Pad 1 is Gate;  
**Pads 2,5,6,9,10,13,14 are Source;**  
**Pads 3,4,7,8,11,12 are Drain**



**RECOMMENDED LAND PATTERN**  
(units in  $\mu\text{m}$ )



Land pattern is solder mask defined.

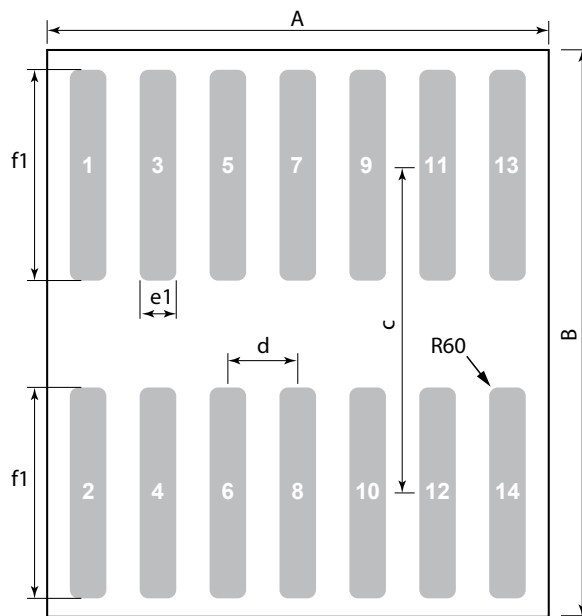
Pad 1 is Gate;

Pads 2,5,6,9,10,13, 14 are Source;

Pads 3,4,7,8,11,12, are Drain

DIM	Micrometers
<b>A</b>	2850
<b>B</b>	3250
<b>c</b>	1805
<b>d</b>	400
<b>e1</b>	180
<b>f1</b>	1175

**RECOMMENDED STENCIL DRAWING**  
(units in  $\mu\text{m}$ )



DIM	Micrometers
<b>A</b>	2850
<b>B</b>	3250
<b>c</b>	1805
<b>d</b>	400
<b>e1</b>	180
<b>f1</b>	1175

Recommended stencil should be 4 mil (100  $\mu\text{m}$ ) thick, , laser cut stainless steel, opening per drawing.

The corner has a radius of R60.

Intended for use with SAC305 Type 4 solder, reference 88.5% metals content.

Additional assembly resources available at <https://epc-co.com/epc/design-support>

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